

REMARKS

Reconsideration of the present application is requested.

Each of claims 1, 7 and 8 has been amended in response to the rejection of those claims as being indefinite.

In particular, each of claims 1 and 7 defines the elements (A1) and (A2) in terms of an XPS measurement and recites that they are elements other than metals.

In addition, XPS has been defined as X-ray photoelectron spectroscopy.

Furthermore, the surface which is employed to measure the depths of atoms has been defined in claims 1 and 7 as the surface of the polymer base (D) which is in contact with the reflective layer (the reflective layer defined as having a laminate structure of at least a high refractive index layer (A), a low refractive index layer (B), and a metal layer (C)). Thus, the surface in question is the surface of the polymer base which is in contact with the laminate structure.

Furthermore, that definition of the surface in question obviates the objection to the drawing, as the identity of such surface is evident in the original figures.

Claim 7 now recites the step of "forming" a reflective layer on a polymer base and thus constitutes a proper method claim, i.e., a statutory class of invention.

In light of the foregoing, it is submitted that the application is in condition for allowance.

Respectfully submitted,

BUCHANAN INGERSOLL & ROONEY PC

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By:

A handwritten signature in black ink, appearing to read 'Alan E. Kopecki', written over a horizontal line.

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